

RELIABILITY MONITOR

PROCESS: 0.6 μ m Double Poly, Single Metal (Ti/TiN layers u

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2502	C2	DEC '98	P23041	9842	CARSEM	DM821478AIB	8 PIN SOIC	48	228	0

TOTALS FOR: 0.6 μ m Double Poly, Single Metal (Ti/Ti FAIL RATE (Fits): 240 DEVICE HRS: 3.82E+06 0

RELIABILITY MONITOR

PROCESS: 0.8 μ m Double Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153Q	A7	DEC '98	P23108	9833	ANAM-KOREA (AICL)	DN811539AAB	44 PIN PLCC	48	237	0
DS2153Q	A7	SEP '98	P22556	9749	ANAM-KOREA (AICL)	DN733468AAB	44 PIN PLCC	48	236	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153Q	A7	SEP '98	P22637	9749	ANAM-KOREA (AICL)	DN733468AAB	44 PIN PLCC	336	77	0
DS2153Q	A7	SEP '98	P22637	9749	ANAM-KOREA (AICL)	DN733468AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 0.8 μ m Double Poly, Single Metal FAIL RATE (Fits): 72 DEVICE HRS: 1.28E+07 0

RELIABILITY MONITOR

PROCESS: 0.8 µm Single Poly, Double Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A3	JUN '98	P22282	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	48	234	0
DS1302Z	A3	SEP '98	P22691	9829	ANAM-PI (ATP/AAPI)	DK817643ACA	8 PIN PDIP	48	234	0
DS1315	B1	SEP '98	P22496	9825	ANAM-PI (ATP/AAPI)	DK806519AAA	16 PIN PDIP	48	234	0
DS17485	A2	MAY '98	P22308	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	48	230	0
DS17485	A2	AUG '98	P22472	9819	ANAM-KOREA (AICL)	DN807687AAA	24 PIN SOIC	48	233	0
DS17485	A2	FEB.'98	P22032	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	48	230	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A3	JUN '98	P22349	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	336	77	0
DS1302	A3	JUN '98	P22349	9808	ANAM-KOREA (AICL)	DN750310AB	8 PIN SOIC	1000	77	0
DS1302Z	A3	SEP '98	P22734	9829	ANAM-PI (ATP/AAPI)	DK817643ACA	8 PIN PDIP	336	77	0
DS1302Z	A3	SEP '98	P22734	9829	ANAM-PI (ATP/AAPI)	DK817643ACA	8 PIN PDIP	1000	77	0
DS1315	B1	SEP '98	P22536	9825	ANAM-PI (ATP/AAPI)	DK806519AAA	16 PIN PDIP	336	77	0
DS1315	B1	SEP '98	P22536	9825	ANAM-PI (ATP/AAPI)	DK806519AAA	16 PIN PDIP	1000	77	0
DS17485	A2	AUG '98	P22526	9819	ANAM-KOREA (AICL)	DN807687AAA	24 PIN SOIC	336	77	0
DS17485	A2	MAY '98	P22467	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	336	77	0
DS17485	A2	FEB.'98	P22303	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	336	77	0
DS17485	A2	FEB.'98	P22303	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	1000	76	0

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DS17485	A2	AUG '98	P22526	9819	ANAM-KOREA (AICL)	DN807687AAA	24 PIN SOIC	1000	77	0
DS17485	A2	MAY '98	P22467	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	1000	77	0

TOTALS FOR: 0.8 μ m Single Poly, Double Metal FAIL RATE (Fits): 6 DEVICE HRS: 1.45E+08 0

RELIABILITY MONITOR

PROCESS: 0.8 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232L	C1	OCT '98	P22755	9830	HYUNDAI-KOREA (HEI)	DL817678ABB	8 PIN SOIC	48	232	0
DS1232S	C1	JUL '98	P22324	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	48	234	0
DS1620	D1	JUN '98	P22198	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	48	237	0
DS1620	D1	SEP '98	P22599	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	48	230	0
DS1621	A7	SEP '98	P22590	9807	ANAM-KOREA (AICL)	DN744346ABA	8 PIN SOIC	48	236	0
DS1621	A5	JUN '98	P22200	9745	CARSEM	DM734572AA	8 PIN SOIC	48	237	0
DS1621	A5	MAR '98	P22276	9749	CARSEM	DM705419AB	8 PIN SOIC	48	230	0
DS2109S	A7	DEC '98	P23110	9836	CARSEM	DM811524AA-	28 PIN SOIC	48	233	0
DS21S07	E	NOV '98	P22912	9825	ANAM-PI (ATP/AAPI)	DK809216AC	20 PIN TSSOP	48	231	0
DS21S07	E	AUG '98	P22466	9820	CARSEM	DM807703AA	20 PIN TSSOP	48	234	0
DS2401	B2	SEP '98	P22504	9814	CARSEM	DM747716AC	TO-92	48	234	0
DS2401	B2	DEC '98	P22908	9815	CARSEM	DM803085AA	TO-92	48	234	0
DS2434	D1	NOV '98	P22801	9827	CARSEM	DM809170AA	TO-226 (PR-35)	48	237	0
DS2502	B6	SEP '98	P22573	9827	CARSEM	DM811458AA	8 PIN SOIC	48	233	0
DS80320	B5	OCT '98	P22690	9823	ANAM-PI (ATP/AAPI)	DK810423AAB	40 PIN PDIP	48	234	0
DS80320	B5	JUL '98	P22230	9815	ANAM-PI (ATP/AAPI)	DK804253AAA	40 PIN PDIP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
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DS1232L	C1	OCT '98	P22778	9830	HYUNDAI-KOREA (HEI)	DL817678ABB	8 PIN SOIC	336	77	0
DS1232L	C1	OCT '98	P22778	9830	HYUNDAI-KOREA (HEI)	DL817678ABB	8 PIN SOIC	1000	77	0
DS1232S	C1	JUL '98	P22370	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	336	77	0
DS1232S	C1	JUL '98	P22370	9821	HYUNDAI-KOREA (HEI)	DL809263AAC	16 PIN SOIC	1000	77	0
DS1620	D1	SEP '98	P22707	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	336	77	0
DS1620	D1	JUN '98	P22287	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	336	77	0
DS1620	D1	SEP '98	P22707	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	1000	77	0
DS1620	D1	JUN '98	P22287	9741	ALPHTK-BANGKOK(NSE	DJ723284AAF	8PN SOIC, 208MIL	1000	77	0
DS1621	A7	SEP '98	P22656	9807	ANAM-KOREA (AICL)	DN744346ABA	8 PIN SOIC	336	77	0
DS1621	A7	SEP '98	P22656	9807	ANAM-KOREA (AICL)	DN744346ABA	8 PIN SOIC	1000	77	0
DS1621	A5	MAR '98	P22342	9749	CARSEM	DM705419AB	8 PIN SOIC	336	68	0
DS1621	A5	JUN '98	P22283	9745	CARSEM	DM734572AA	8 PIN SOIC	336	71	0
DS1621	A5	JUN '98	P22283	9745	CARSEM	DM734572AA	8 PIN SOIC	1000	71	0
DS1621	A5	MAR '98	P22342	9749	CARSEM	DM705419AB	8 PIN SOIC	1000	67	0
DS21S07	E	AUG '98	P22488	9820	CARSEM	DM807703AA	20 PIN TSSOP	336	77	0
DS21S07	E	AUG '98	P22488	9820	CARSEM	DM807703AA	20 PIN TSSOP	1000	77	0
DS2401	B2	DEC '98	P22922	9815	CARSEM	DM803085AA	TO-92	336	77	0
DS2401	B2	SEP '98	P22532	9814	CARSEM	DM747716AC	TO-92	336	77	0
DS2401	B2	DEC '98	P22922	9815	CARSEM	DM803085AA	TO-92	1000	77	0
DS2401	B2	SEP '98	P22532	9814	CARSEM	DM747716AC	TO-92	1000	77	0
DS2502	B6	SEP '98	P22633	9827	CARSEM	DM811458AA	8 PIN SOIC	336	77	0
DS2502	B6	SEP '98	P22633	9827	CARSEM	DM811458AA	8 PIN SOIC	1000	77	0
DS80320	B5	JUL '98	P22309	9815	ANAM-PI (ATP/AAPI)	DK804253AAA	40 PIN PDIP	336	77	0
DS80320	B5	OCT '98	P22728	9823	ANAM-PI (ATP/AAPI)	DK810423AAB	40 PIN PDIP	336	77	0
DS80320	B5	JUL '98	P22309	9815	ANAM-PI (ATP/AAPI)	DK804253AAA	40 PIN PDIP	1000	77	0

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DS80320 B5 OCT '98 P22728 9823 ANAM-PI (ATP/AAP) DK810423AAB 40 PIN PDIP 1000 77 0

TOTALS FOR: 0.8 μ m Single Poly, Single Metal FAIL RATE (Fits): 2 DEVICE HRS: 3.87E+08 0

RELIABILITY MONITOR

PROCESS: 1.2 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	JUL '98	P22421	9828	CARSEM	DM819256AB	SOT-223	48	229	0
DS1233Z	A5	OCT '98	P22753	9836	CARSEM	DM819258AC	SOT-223	48	229	0
DS1267	A1	AUG '98	P22597	9824	ANAM-PI (ATP/AAPI)	DK745514AB	20 PIN TSSOP	48	229	0
DS1267E	A1	NOV '98	P23026	9823	ANAM-PI (ATP/AAPI)	DK803107AAE	20 PIN TSSOP	48	233	0
DS1620	C1	MAR '98	P22173	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	48	232	0
DS2165Q	B1	OCT '98	P22757	9837	ANAM-KOREA (AICL)	DN811583AAB	28 PIN PLCC	48	236	0
DS5002	B3	OCT '98	P22751	9831	CARSEM	DM817638AAF	80 PIN PQFP	48	198	0
DS5002	B3	JUL '98	P22364	9822	CARSEM	DM808095AA	80 PIN PQFP	48	199	0
DS5002	B3	APR '98	P22249	9806	CARSEM	DM743264AA	80 PIN PQFP	48	199	0
DS5002F	A3	JAN.'98	P21352	9738	CARSEM	DM720028AA	80 PIN PQFP	48	199	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	JUL '98	P22521	9828	CARSEM	DM819256AB	SOT-223	336	77	0
DS1233	A5	JUL '98	P22521	9828	CARSEM	DM819256AB	SOT-223	1000	77	0
DS1233Z	A5	OCT '98	P22782	9836	CARSEM	DM819258AC	SOT-223	336	77	0
DS1233Z	A5	OCT '98	P22782	9836	CARSEM	DM819258AC	SOT-223	1000	77	0
DS1267	A1	AUG '98	P22660	9824	ANAM-PI (ATP/AAPI)	DK745514AB	20 PIN TSSOP	336	77	0
DS1267	A1	AUG '98	P22660	9824	ANAM-PI (ATP/AAPI)	DK745514AB	20 PIN TSSOP	1000	77	0

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DS1620	C1	MAR '98	P22271	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	336	72	0
DS1620	C1	MAR '98	P22271	9746	ALPHTK-BANGKOK(NSE	DJ723286AAC	8PN SOIC, 208MIL	1000	72	0
DS5002	B3	APR 98 '	P22319	9806	CARSEM	DM743264AA	80 PIN PQFP	336	77	0
DS5002	B3	OCT '98	P22769	9831	CARSEM	DM817638AAF	80 PIN PQFP	336	77	0
DS5002	B3	JUL '98	P22441	9822	CARSEM	DM808095AA	80 PIN PQFP	336	77	0
DS5002	B3	APR 98 '	P22319	9806	CARSEM	DM743264AA	80 PIN PQFP	1000	77	0
DS5002	B3	OCT '98	P22769	9831	CARSEM	DM817638AAF	80 PIN PQFP	1000	77	0
DS5002	B3	JUL '98	P22441	9822	CARSEM	DM808095AA	80 PIN PQFP	1000	77	0

TOTALS FOR: 1.2 µm Single Poly, Single Metal

FAIL RATE (Fits): 5 DEVICE HRS: 2.01E+08 0

RELIABILITY MONITOR

PROCESS: 2.0 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JUL '98	P22328	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	48	234	0
DS2181	A2	AUG '98	P22480	9808	ANAM-KOREA (AICL)	DN751456AAC	44 PIN PLCC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JUL '98	P22402	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	336	77	0
DS2175S	D1	JUL '98	P22402	9811	ANAM-KOREA (AICL)	DN803119AAE	16 PIN SOIC	1000	77	0
DS2181	A2	AUG '98	P22918	9808	ANAM-KOREA (AICL)	DN751456AAC	44 PIN PLCC	336	77	0
DS2181	A2	AUG '98	P22918	9808	ANAM-KOREA (AICL)	DN751456AAC	44 PIN PLCC	1000	77	0

TOTALS FOR: 2.0 μ m Single Poly, Single Metal FAIL RATE (Fits): 15 DEVICE HRS: 6.15E+07 0

RELIABILITY MONITOR

PROCESS: 3.0 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210S	C1	JUL '98	P22330	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210S	C1	JUL '98	P22398	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	336	77	0
DS1210S	C1	JUL '98	P22398	9813	ANAM-KOREA (AICL)	DN801581AAC	16 PIN SOIC	1000	77	0

TOTALS FOR: 3.0 μ m Single Poly, Single Metal FAIL RATE (Fits): 30 DEVICE HRS: 3.08E+07 0

RELIABILITY MONITOR

PROCESS: 5.0 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	AUG '98	P22456	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	48	234	0
DS232	B3	SEP '98	P22499	9809	OMEDATA	DD747726AAA	16 PIN PDIP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	AUG '98	P22484	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	336	77	0
DS2108	B1	AUG '98	P22484	9747	ANAM-KOREA (AICL)	DN722653BA	24 PIN SOIC	1000	77	0
DS232	B3	SEP '98	P22545	9809	OMEDATA	DD747726AAA	16 PIN PDIP	336	77	0
DS232	B3	SEP '98	P22545	9809	OMEDATA	DD747726AAA	16 PIN PDIP	1000	77	0

TOTALS FOR: 5.0 μ m Single Poly, Single Metal FAIL RATE (Fits): 22 DEVICE HRS: 4.22E+07 0